

**Search Notes**

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Shih-wen Hsieh

Applicant(s)/Patent under  
Reexamination

TAKANO ET AL.

Art Unit

2861

**SEARCHED**

Class	Subclass	Date	Examiner
updated	updated	6/20/2005	SWH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR